

Applicant : Ares Rosakis, et al.

Art Unit: 2877

Serial No.: 10/766,512

Filed: January 27, 2004

Title : ANALYSIS AND MONITORING OF STRESSES IN EMBEDDED

LINES AND VIAS INTEGRATED ON SUBSTRATES

Commissioner for Patents P.O. Box 1450

Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Dear Sir:

MOV 0 1 2004

Applicants call attention to the attached Information

Disclosure Statement and documents listed on form PTO-1449.

This filing is being made before the receipt of a first Office action on the merits. No fee is required.

Consideration of the foregoing and enclosure plus the return of a copy of the enclosed form PTO-1449 with the Examiner's initials in the left column per MPEP 609 are earnestly solicited along with an early action on the merits.

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S. Department of Commerce Patent and Trademark Office

Attorney's Docket No. 06618-929001

Application No. 10/766,512

17ADEMARK Information Disclosure Statement by Applicant (Use several sheets if necessary)

Applicant

Ares Rosakis, et al.

Filing Date January 27, 2004 Group Art Unit 2877

(37 CFR §1.98(b))

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	6031611	2/29/2000	Rosakis, et al.			
	AB	6469788	10/22/2002	Boyd, et al.			
	AC	6513389	2/4/2003	Suresh, et al.			
	AD	6600565	7/29/2003	Suresh, et al.			
	AE	2004/0075825	4/22/2004	Suresh, et al.			
	AF	6781702	8/24/2004	Giannakopoulos, et al.			
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner	Desig.	Document	Publication	Country or			Translation	
Initial	ID	Number	Date	Patent Office	Class	Subclass	Yes	No
	AM							
	AN							
	AO							
	AP							
	AQ							

Other Documents (include Author, Title, Date, and Place of Publication)			
Examiner	Desig.		
Initial	ID	Document	
	AR	Wikstrom, et al.; Thermoelastic analysis of periodic thin lines deposited on a substrate; 1999; Journal of the Mechanics and Physics of Solids, 47 (1999); pps 1113-1130	
	AS		
	AT		
	AU		

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if next communication to applicant.	ot in conformance and not considered. Include copy of this form with